

Search Notes

Application No.

10/036,501

Examiner

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Applicant(s)

HEGER ET AL.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
382	100, 115, 116, 103, 154-155	10/29/04	SLC
	164, 165, 173,		
	181, 276		
235	419		
"	420- 423		
356	12, 21,		
"	22		
348	77, 169		
345	419, 418 427		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Exam, USPAT, US-P&Pub, EPO, JPO Derwent, IBM-TDB.	10/27/04	SLC
IEEE, Invention Name Search	"	"